

SLOVENSKI STANDARD SIST EN 62343-5-1:2009

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Dynamic modules - Test methods - Part 5-1: Dynamic gain tilt equalizer - Response time measurement (IEC 62343-5-1:2009)

Dynamische Module - Prüfverfahren - Teil 5-1: Equalizer zur Kompensation einer dynamischen Verstärkerkennlinie - Messung der Antwortzeit (IEC 62343-5-1:2009)

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Modules dynamiques - Méthodes d'essais - Partie 5-1: Egaliseur dynamique de basculement de gain - Mesure du temps de réponse (CEI 62343-5-1:2009)

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Ta slovenski standard je istoveten z: EN 62343-5-1-2009

ICS:

33.180.30 U] cã } ã hæ ^çæ } ã a Optic amplifiers

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EUROPEAN STANDARD

EN 62343-5-1

NORME FUROPÉENNE **EUROPÄISCHE NORM**

September 2009

ICS 33.180.01;33.180.99

English version

Dynamic modules -Test methods -Part 5-1: Dynamic gain tilt equalizer -Response time measurement

(IEC 62343-5-1:2009)

Modules dynamiques -Méthodes d'essais -

Partie 5-1: Egaliseur dynamique

de basculement de gain -Mesure du temps de réponse

(CEI 62343-5-1:2009) Teh STANDARD P(IEC 62343-5-1:2009)

Dynamische Module -Prüfverfahren -

Teil 5-1: Equalizer zur Kompensation einer dynamischen Verstärkerkennlinie -

Messung der Antwortzeit

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This European Standard was approved by CENELEC on 2009-08-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

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CENELEC

European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: Avenue Marnix 17, B - 1000 Brussels

Foreword

The text of document 86C/883/FDIS, future edition 1 of IEC 62343-5-1, prepared by SC 86C, Fibre optic systems and active devices, of IEC TC 86, Fibre optics, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 62343-5-1 on 2009-08-01.

The following dates were fixed:

 latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement

(dop) 2010-05-01

 latest date by which the national standards conflicting with the EN have to be withdrawn

(dow) 2012-08-01

Endorsement notice

The text of the International Standard IEC 62343-5-1:2009 was approved by CENELEC as a European Standard without any modification.

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IEC 62343-5-1

Edition 1.0 2009-06

INTERNATIONAL STANDARD

Dynamic modulesi Test methods DARD PREVIEW
Part 5-1: Dynamic gain tilt equalizer – Response time measurement

<u>SIST EN 62343-5-1:2009</u> https://standards.iteh.ai/catalog/standards/sist/aa3e782a-5482-4a70-b70f-a1a9fe1f75ba/sist-en-62343-5-1-2009

INTERNATIONAL ELECTROTECHNICAL COMMISSION

PRICE CODE

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ICS 33.180.01; 33.180.99

ISBN 2-8318-1050-7

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DYNAMIC MODULES -TEST METHODS -

Part 5-1: Dynamic gain tilt equalizer – Response time measurement

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International Standard IEC 62343-5-1 has been prepared by subcommittee 86C: Fibre optic systems and active devices, of IEC technical committee 86: Fibre optics.

The text of this standard is based on the following documents:

FDIS	Report on voting
86C/883/FDIS	86C/899/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts of IEC 62343 series, published under the general title *Dynamic modules* – *Test methods*, can be found on the IEC website.

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The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- · reconfirmed,
- withdrawn,
- · replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

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DYNAMIC MODULES -TEST METHODS -

Part 5-1: Dynamic gain tilt equalizer – Response time measurement

1 Scope and general information

1.1 Scope

This part of IEC 62343 contains the measurement method of response time for a dynamic gain tilt equalizer (DGTE) to change its gain tilt from an arbitrary initial value to a desired target value.

1.2 General information

The DGTE is categorized into three control methods as shown in Table 1. The direct control type is driven directly by voltage or current, the digital control type is operated by digital control system with digital signals, and the analogue control type is operated by analogue signals. The definition and the measurement method of response time for DGTE are different for the three control types. Table 1 also shows the configuration of operating systems and the correction for temperature dependency for three control types of DGTE. When the response time for the DGTE has temperature dependency, users may need to calibrate the temperature effect. The bottom row in Table 1 indicates the typical methods of the correction for temperature dependency (refer to Annex D). 62343-5-1:2009

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Direct control Digital control Analogue control Control By voltage or current By command through digital By voltage or current directly circuit through analogue circuit Configurations DGTE DGTE **DGTE** w/digital circuit w/analogue circuit V/I applied Command V/I control I2C, (RS232c, (ex. 0~+5V) Control system Control system Control system Correction for By control system By digital circuit or control By analogue circuit or temperature system control system dependency

Table 1 - Categorization of DGTE by the control method

2 Terms, definitions, abbreviations and response waveforms

2.1 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

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2.1.1

convergence time

 T_{c}

time to converge from the first hit at the target $\pm Y$ % to the stay within the deviation $\pm Y$ % in the optical power from the output port of DGTE at pre-determined wavelength

2.1.2

latency time

 T_{I}

for the direct and the analogue control types, time between the application of control signal and the change in optical power by $\pm X$ % from the output port of DGTE at pre-determined wavelength

2.1.3

processing time

 T_{p}

for the digital control type, time between the application of control command and the change in optical power by $\pm X$ % from the output port of DGTE at pre-determined wavelength

2.1.4

response time

 $(T_{\rm I} \text{ or } T_{\rm D}) + T_{\rm r} + T_{\rm C}$

2.1.5 rise time

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rise t T.

time to change from the initial ±x % to the target ±x % in the optical power from the output port of DGTE at pre-determined wavelength

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setting time ala9fe1f75ba/sist-en-62343-5-1-2009

 T_{c}

time to be suppressed from the first hit at the target $\pm Y$ % to the final stay at the target within a required resolution of the optical power from the output port of DGTE at pre-determined wavelength

2.2 Abbreviations

CPU Central processing unit

DGTE Dynamic gain tilt equalizer

DUT Device under test
O/E Optical-to-electrical

PDL Polarization dependent loss

TLS Tunable laser source

WDM Wavelength division multiplexing

2.3 Response waveforms

The definitions and symbols defined in 2.1 are shown in Figures 1 through Figure 3.